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Reply to Missing Parts/ Incomplete Application

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Document(s)

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TRANSMITTAL FORM			Application Number	10/612,133						
			Filing Date	07/02/2003 Miles et al.						
			First Named Inventor							
			Art Unit	2878						
(to be used for all correspondence after initial filing)			Examiner Name	Thanh 2	X. Luu					
Total Number of Pages in This Submission			Attorney Docket Number	SHP-P	T077					
ENCLOSURES (Check all that apply)										
	Fee Attached Amendment/Reply After Final Affidavits/declaration(s) Extension of Time Request Express Abandonment Request Supplemental		Drawing(s) Licensing-related Papers Petition Petition to Convert to a Provisional Application Power of Attorney, Revocation Change of Correspondence Address Ferminal Disclaimer Request for Refund		Form	After Allowance Communication to TC Appeal Communication to Board of Appeals and Interferences Appeal Communication to TC (Appeal Notice, Brief, Reply Brief) Proprietary Information Status Letter Other Enclosure(s) (please Identify below): n PTO-1449; 13 references				
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	SIGNATURE OF A	PPLICANT, ATTORNEY, (OR AGENT	
Firm Name	VOLPE AND KOENIG, P.C.	,		
Signature	Ryan W. D'Sau			
Printed name	Ryan W. O'Donnell			
Date	March 22,2007	Reg. No.	53,401	

CERTIFICATE OF TRANSMISSION/MAILING

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This collection of information is required by 37 CFR 1.5. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.11 and 1.14. This collection is estimated to 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria. VA 22313-1450

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Our File: SHP-PT077

Date: March 22, 2007

MAR 27 2001 WILL UNITED STATES PATENT AND TRADEMARK OFFICE

In the PATENT APPLICATION of:

Mervyn J. Miles et al.

Application No.:

10/612,133

Confirmation No.: 3323

Filed:

July 2, 2003

For: RESO

RESONANT SCANNING PROBE

MICROSCOPE Group: 2

2878

Examiner:

Thanh X. Luu

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Further to Applicants' Duty of Disclosure pursuant to 37 C.F.R. §1.56, Applicants wish to bring to the Examiner's attention the material cited on the enclosed PTO-1449 form. Pursuant to 37 C.F.R. §1.98(a)(2)(ii), copies of the cited U.S. publications and/or patent documents have not been included.

It is respectfully requested that the Examiner consider these documents and return an initialed copy of the PTO-1449 form indicating his consideration of the cited materials.

Respectfully submitted,

Miles et al.

Ryan W. O'Donnell

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Sheet _1_ of _1 FORM PTO-1449 ATTY. DOCKET NO. SERIAL NO. SHP-PT077 10/612,133 U.S. DEPARTMENT OF COMMERCE **APPLICANT** PATENT AND TRADEMARK OFFICE Mervyn J. Miles et al. INFORMATION DISCLOSURE **FILING DATE GROUP** STATEMENT BY APPLICANT 07/02/2003 2878 (Use several sheets if necessary) **U.S. PATENT DOCUMENTS** FILING DATE IF APPROPRIATE FYAMINER DOCUMENT NUMBER DATE CLASS SUBCLASS AA 11/1972 3,702,398 Van-Essen et al. Elings et al. AB 5,412,980 05/1995 AC 5,566,159 10/1996 Shapira ΑD 6.094.971 08/2000 Edwards et al. 05/2001 AΕ 6,236,783 Mononobe et al. FOREIGN PATENT DOCUMENTS TRANSI ATION DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS VES NO ΑI 0 8 9 9 9/1998 6 4 8 Europe 09/2003 AF 5 4 5 5 3 8 **A1** Europe 9 5 3 66 10/1996 AG 1 1 4 Germany 9 5 2 33 AΗ 1 8 8 5/2000 Germany AJ 2 0 0 4 5 19 1/2001 X* 1 Japan X* ΑK 2 0 0 0 19 97 36 7/2000 Japan OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) M. Antognozzi, et al., A New Method To Measure The Oscillation Of A Cylindrical Cantilever: "The Laser AL Reflection Detection System," 04/2000, Review of Scientific Instruments, Volume 71, No. 4, pp 1689-1694 S.K. Sekatskii, et al., Time-Gated Scanning Near-Field Optical Microscopy, 10/2/2000, Applied Physics AM Letters, Volume 77, No. 14, pp 2089-2091 S.H. Simpson, et al., Analysis Of The Effect Arising From The Near-Field Optical Microscopy Of AN Homogeneous Dielectric Slabs, 09/1/2001, Optics Communications 196, pp 17-31 Khaled Karrai, et al., Piezoelectric tip-sample control for near field optical microscopes, 04/3/1995, American AO Institute of Physics, Vol. 66, No. 14, pp 1842-1844 Claire E. Jordan, et al., Removing optical artifacts in near-field scanning optical microscopy by using a three-AP dimensional scanning mode, 09/1/1999, Journal of Applied Physics, Vol. 86, No. 5, pp 2785-2789 Oshikane et al., Scanning Near-Field Optical Microscope With A Small Spherical Protrusion Probe Excited AQ With WGM Resonances, Optical Memory & Neural Networks 2000, Vol. 9, No. 3, pp 147-168 Oshikane et al., 3D-FDTD and experimental analysis of a resonant microcavity probe for high-resolution AR SNOM, Physics Devices & Information Processing, 07/1999, Vol. 3791, pp 57-62 DATE CONSIDERED **EXAMINER**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.